

Si-Ag Composite Fabrication for Infrared Detector

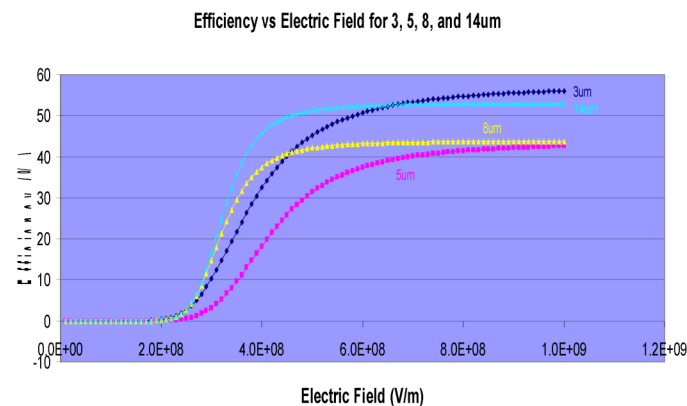
SIGNIFICANT FINDINGS:

Objective:

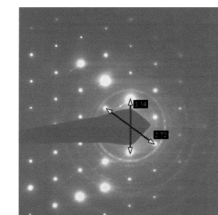
1. Fabricating an infrared detectors covering three atmospheric windows;
2. Compatible with current processing technology;
3. Easy for integration;

AUTHOR(S):

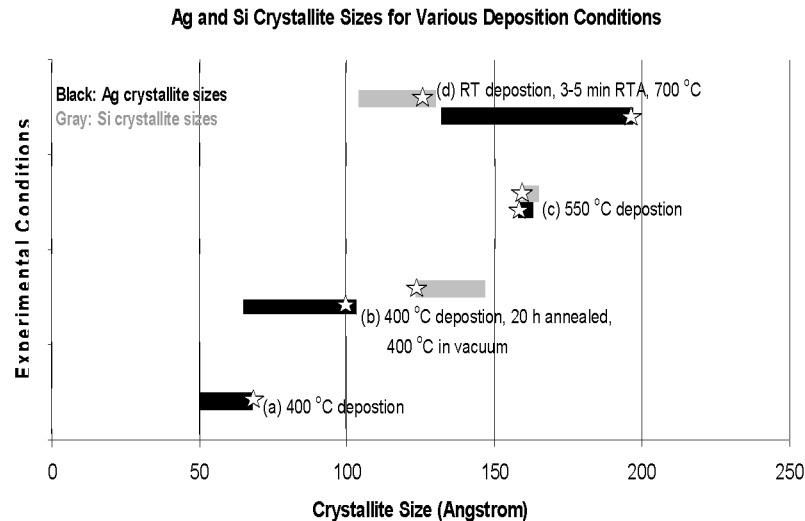
Chichang Zhang and Clayton W. Bates Jr.
Department of ECE
Howard University, Washington, D.C.



BIS [ETHYL 3-N(ISOPROPYL)-BUTANOATO] ZINC (II)



TEM/ELECTRON
DIFFRACTION
PATTERN FOR
SAMPLE Ag/N-Si
DEPOSITED AT
550°C.



AG AND SI CRYSTALLITE SIZES UNDER VARIOUS EXPERIMENTAL CONDITIONS. (A) 400oC DEPOSITION; (B) 400oC DEPOSITION FOLLOWED BY 400oC 20 HOURS ANNEALING IN VACUUM; (C) 550oC DEPOSITION; (D) ROOM TEMPERATURE (RT) DEPOSITION FOLLOWED BY RTA AT 700oC FOR 3-5 MINUTES. THE AVERAGE CRYSTALLITES SIZES WERE MARKED WITH STARS.